

**MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
Collector-Emitter Voltage	$V_{CE0}$	30	Vdc
Collector-Base Voltage	$V_{CB0}$	60	Vdc
Emitter-Base Voltage	$V_{EB0}$	5.0	Vdc
Collector Current — Continuous	$I_C$	500	mAdc
		One Die	Both Die Equal Power
Total Device Dissipation @ $T_A = 25^\circ\text{C}$ Derate above $25^\circ\text{C}$	$P_D$	575 3.29	625 3.57 mW mW/°C
Total Device Dissipation @ $T_C = 25^\circ\text{C}$ Derate above $25^\circ\text{C}$	$P_D$	1.8 10.3	2.5 14.3 Watts mW/°C
Operating and Storage Junction Temperature Range	$T_J, T_{stg}$	-65 to +200	°C

**THERMAL CHARACTERISTICS**

Characteristic	Symbol	One Die	Both Die Equal Power	Unit
Thermal Resistance, Junction to Case	$R_{\theta JC}$	97	70	°C/W
Thermal Resistance, Junction to Ambient	$R_{\theta JA(1)}$	304	280	°C/W
		Junction to Ambient	Junction to Case	
Coupling Factors		84	44	%

(1)  $R_{\theta JA}$  is measured with the device soldered into a typical printed circuit board.

**ELECTRICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$  unless otherwise noted.)**

Characteristic	Symbol	Min	Typ	Max	Unit
<b>OFF CHARACTERISTICS</b>					
Collector-Emitter Breakdown Voltage ( $I_C = 10 \mu\text{Adc}, I_B = 0$ )	$V_{(BR)CEO}$	30	—	—	Vdc
Collector-Base Breakdown Voltage ( $I_C = 10 \mu\text{Adc}, I_E = 0$ )	$V_{(BR)CBO}$	60	—	—	Vdc
Emitter-Base Breakdown Voltage ( $I_E = 10 \mu\text{Adc}, I_C = 0$ )	$V_{(BR)EBO}$	5.0	—	—	Vdc
Collector Cutoff Current ( $V_{CB} = 50 \text{Vdc}, I_E = 0$ )	$I_{CBO}$	—	—	10	nAdc
				10	$\mu\text{Adc}$
Emitter Cutoff Current ( $V_{BE} = 3.0 \text{Vdc}, I_C = 0$ )	$I_{EBO}$	—	—	10	nAdc
<b>ON CHARACTERISTICS</b>					
DC Current Gain(2) ( $I_C = 10 \mu\text{Adc}, V_{CE} = 10 \text{Vdc}$ ) ( $I_C = 100 \mu\text{Adc}, V_{CE} = 10 \text{Vdc}$ ) ( $I_C = 1.0 \text{mAdc}, V_{CE} = 10 \text{Vdc}$ ) ( $I_C = 10 \text{mAdc}, V_{CE} = 10 \text{Vdc}$ )	$h_{FE}$				—
		20	40	100	
		30	50	120	
		40	60	160	
		50	65	200	
Collector-Emitter Saturation Voltage ( $I_C = 10 \text{mAdc}, I_B = 1.0 \text{mAdc}$ )	$V_{CE(sat)}$	—	0.09	0.15	Vdc
Base-Emitter Saturation Voltage ( $I_C = 10 \text{mAdc}, I_B = 1.0 \text{mAdc}$ )	$V_{BE(sat)}$	—	0.7	0.85	Vdc
<b>SMALL-SIGNAL CHARACTERISTICS</b>					
Current-Gain — Bandwidth Product ( $I_C = 20 \text{mAdc}, V_{CE} = 20 \text{Vdc}, f = 100 \text{MHz}$ )	$f_T$	200	250	—	MHz
Output Capacitance ( $V_{CB} = 10 \text{Vdc}, I_E = 0, f = 1.0 \text{MHz}$ )	$C_{obo}$	—	3.5	8.0	pF
Input Capacitance ( $V_{BE} = 0.5 \text{Vdc}, I_C = 0, f = 1.0 \text{MHz}$ )	$C_{ibo}$	—	15	25	pF
<b>MATCHING CHARACTERISTICS</b>					
Base-Emitter Voltage Differential Change Due to Temperature ( $I_C = 100 \mu\text{Adc}, V_{CE} = 10 \text{Vdc}$ , $T_A = -55^\circ\text{C}$ to $+25^\circ\text{C}$ )	$ V_{BE1} - V_{BE2} $	—	—	1.6	mVdc
		—	—	0.8	
( $I_C = 100 \mu\text{Adc}, V_{CE} = 10 \text{Vdc}$ , $T_A = +25^\circ\text{C}$ to $+125^\circ\text{C}$ )		—	—	2.0	
		—	—	1.0	

(2) Pulse Test: Pulse Width  $\leq 300 \mu\text{s}$ , Duty Cycle  $\leq 2.0\%$ .

# MD3409 MD3410

CASE 654-07, STYLE 1

**DUAL  
AMPLIFIER TRANSISTORS**

NPN SILICON

Refer to MD2218 for graphs.

